



Product/Process Change Notice - PCN 17_0188 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: ADuM3223/ADuM3224 Die Revision + Test Platform Migration from Harris Tuvey to MPS Mess-& Prüfsysteme GmbH

Publication Date: 11-Sep-2017

Effectivity Date: 10-Dec-2017 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change

Die Changes:

1. Probe pad added to the output driver (IC or non-transformer) die.
2. Polyimide passivation layer added to output driver (IC or non-transformer) die.

Platform Migration:

The MPS high voltage test system will be used as an additional test platform for the ADuM3223 and ADuM3224 products at Analog Devices General Trias (ADGT), Philippines.

Reason For Change

Die Changes:

1. Probe pad added to enable high voltage stress testing of internal Nwell capacitor during production wafer probe.
2. Polyimide offers: enhanced protection against die scratches, package stresses and surface ESD/EOS events.

Platform Migration:

To support capacity, and ensure continuity of supply, the MPS high voltage test option will supplement the Harris-Tuvey in testing the ADuM3223 and ADuM3224.

Impact of the change (positive or negative) on fit, form, function & reliability

There is no change to form, fit or function. The test sequence, methodology and coverage remain unchanged on the new platform.

Summary of Supporting Information

Qualification has been performed per AEC-Q100, Stress Test Qualification for Integrated Circuits. See attached Qualification Results Summary. Test correlation and validation has been performed, see attached Test Correlation report.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_17_0188_Rev_-_ADuM3223W Qualification Results Summary.pdf

Attachment 2: Type: Qualification Results Summary

ADI_PCN_17_0188_Rev_-_ADuM3224W Qualification Results Summary.pdf

Attachment 3: Type: Test Correlation Report

ADI_PCN_17_0188_Rev_-_ADuM3223_24_HT_to_MPS_TestCorrelationReport.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas: PCN_Americas@analog.com

Europe: PCN_Europe@analog.com

Japan: PCN_Japan@analog.com

Rest of Asia: PCN_ROA@analog.com

Appendix A - Affected ADI Models**Added Parts On This Revision - Product Family / Model Number (18)**

ADUM3223 / ADUM3223ARZ	ADUM3223 / ADUM3223ARZ-RL7	ADUM3223 / ADUM3223BRZ	ADUM3223 / ADUM3223BRZ-RL7	ADUM3223 / ADUM3223CRZ
ADUM3223 / ADUM3223CRZ-RL7	ADUM3223 / ADUM3223WARZ	ADUM3223 / ADUM3223WARZ-RL7	ADUM3223 / ADUM3223WBRZ	ADUM3223 / ADUM3223WBRZ-RL7
ADUM3223 / ADUM3223WCRZ	ADUM3223 / ADUM3223WCRZ-RL7	ADUM3224 / ADUM3224WARZ	ADUM3224 / ADUM3224WARZ-RL7	ADUM3224 / ADUM3224WBRZ
ADUM3224 / ADUM3224WBRZ-RL7	ADUM3224 / ADUM3224WCRZ	ADUM3224 / ADUM3224WCRZ-RL7		

Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	11-Sep-2017	10-Dec-2017	Initial Release

Analog Devices, Inc.

DocId:4251 Parent DocId:4249 Layout Rev:7